



NSAI
Standards

Irish Standard
I.S. EN 62047-7:2011

Semiconductor devices - Micro-
electromechanical devices -- Part 7:
MEMS BAW filter and duplexer for radio
frequency control and selection (IEC
62047-7:2011 (EQV))

I.S. EN 62047-7:2011

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**Semiconductor devices -
Micro-electromechanical devices -
Part 7: MEMS BAW filter and duplexer for radio frequency control and
selection
(IEC 62047-7:2011)**

Dispositifs à semiconducteurs -
Dispositifs microélectromécaniques -
Partie 7: Filtre et duplexeur BAW MEMS
pour la commande et le choix des
fréquences radioélectriques
(CEI 62047-7:2011)

Halbleiterbauelemente -
Bauelemente der Mikrosystemtechnik -
Teil 7: BAW-MEMS-Filter und -Duplexer
zur Hochfrequenz-Regelung und -Auswahl
(IEC 62047-7:2011)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 47F/79/FDIS, future edition 1 of IEC 62047-7, prepared by SC 47F, Micro-electromechanical systems, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62047-7 on 2011-07-21.

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The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2012-04-21
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2014-07-21

Endorsement notice

The text of the International Standard IEC 62047-7:2011 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60368-1:2000 + A1:2004	NOTE	Harmonized as EN 60368-1:2000 + A1:2004 (not modified).
IEC 60368-2-2	NOTE	Harmonized as EN 60368-2-2.
IEC 60862-1:2003	NOTE	Harmonized as EN 60862-1:2003 (not modified).
IEC 60862-2	NOTE	Harmonized as EN 60862-2.

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –
MICRO-ELECTROMECHANICAL DEVICES –**
**Part 7: MEMS BAW filter and duplexer
for radio frequency control and selection**

FOREWORD

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International Standard IEC 62047-7 has been prepared by subcommittee 47F: Micro-electromechanical systems, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47F/79/FDIS	47F/87/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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